## Notice of References Cited

Application/Control No. 09/730,656	Reexaminati	Applicant(s)/Patent Under Reexamination BOHMER ET AL.		
Examiner	Art Unit			
Douglas W Owens	2811	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	Α	US-4,243,427	01-1981	DiBugnara, Raymond	106/287.16
X	В	US-5,053,992	10-1991	Gilberg et al.	365/185.04
X	С	US-5,258,334	11-1993	Lantz, II, Leon	438/760
X	۵	US-5,892,661	04-1999	Stafford et al.	361/737
Χ	E	US-6,144,106	11-2000	Bearinger et al.	257/789
	F	US-2002/0033486	03-2002	Kim et al.	257/118
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Laura Peters. September, 1998. Semiconductor International. "Pursuing the Perfect Low - k Dielectric.
	V	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.